

<b>Notice of References Cited</b>	Application/Control No. 10/776,736		Applicant(s)/Patent Under Reexamination DEWAELE, PIET	
	Examiner KATRINA FUJITA		Art Unit 2624	Page 1 of 1

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
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#### FOREIGN PATENT DOCUMENTS

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#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Wuescher et al., "Robust Contour Decomposition Using a Constant Curvature Criterion", Jan. 1991, IEEE Trans. on Pattern Analysis and Machine Intelligence, Vol. 13, No. 1, 41-51
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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